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Bib Data Sheet

CONFIRMATION NO. 7386

SERIAL NUMBER 10/083,399	FILING DATE 02/27/2002 RULE	CLASS 324	GROUP ART UNIT 2858	ATTORNEY DOCKET NO. XA-9640	
APPLICANTS Toshihiro Tanaka, Akiruno, JAPAN; Yutaka Shinagawa, Iruma, JAPAN; Masahiko Kimura, Kodaira, JAPAN; Isao Nakamura, Fussa, JAPAN;					
** CONTINUING DATA ***** <i>none</i>					
** FOREIGN APPLICATIONS ***** <i>yes</i> JAPAN 2001-125275 04/24/2001					
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 04/09/2002					
Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance Verified and Acknowledged <i>one</i> Examiner's Signature Initials		STATE OR COUNTRY JAPAN	SHEETS DRAWING 29	TOTAL CLAIMS 23	INDEPENDENT CLAIMS 5
ADDRESS Miles & Stockbridge P.C. Suite 500 1751 Pinnacle Drive McLean, VA 22102					
TITLE Semiconductor integrated circuit and a method of testing the same					
FILING FEE RECEIVED 1092	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit		